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LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	Applicant: Ulrich Bonne et al.	
	Filing Date: September 26, 2003	Group Art: unknown 2856

U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	
	4,324,566	04/1982	Jacob et al.	
	5,196,039	03/19913	Phillips et al.	
	5,442,175	08/1995	Dawson	
	6,131,440	10/2000	Bertrand	
	6,413,781	07/2002	Geis et al.	

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Country	Translation Yes No

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER:	DATE CONSIDERED: 8/26/07

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U.S. PATENT DOCUMENTS

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✓	3,146,616	09/1964	Loyd			
	3,557,532	01/1971	Broerman			
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	4,228,815	10/1980	Juffa et al.			
	4,478,076	10/1984	Bohrer			
	4,483,200	11/1984	Togawa et al.			
	4,507,974	04/1985	Yelderman			
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	4,735,082	04/1988	Kolloff			
	4,759,210	07/1988	Wohltjen			
	4,909,078	03/1990	Sittler et al.			
	4,944,035	07/1990	Aagardl Roger L., et al.			
	5,031,126	07/1991	McCulloch et al.			
	5,044,766	09/1991	Stuart			
	5,056,047	10/1991	Sondergeld			
	5,146,414	09/1992	McKown et al.			
	5,243,858	09/1993	Erskine et al.			
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	5,463,899	11/1995	Zemel et al.			
	5,533,412	07/1996	Jerman et al.			
	5,587,520	12/1996	Rhodes			
✓	5,922,974	07/1999	Davidson et al.			
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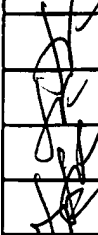
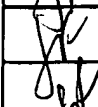
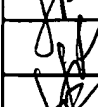

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JL	6,139,384	10/2000	DeTemple et al.			
JL	6,178,811	01/2001	Bonne et al.			
JL	6,194,833	02/2001	DeTemple et al.			
JL	6,308,553	10/2001	Bonne et al.			
JL	6,393,894	05/2002	Bonne et al.			
JL	6,494,617	12/2002	Stokes et al.			




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JL	DE 196 19 133 A1	11/13/97	Germany	Abstract
JL	DE 2 934 566 A1	03/19/81	Germany	Abstract
JL	DE 32 34 146 A1	03/15/84	Germany	Abstract
JL	DE 42 22 458 A1	01/13/94	Germany	Abstract
JL	DE 42 43 573 A1	06/23/94	Germany	Abstract
JL	DE 296 07 315 U1	09/26/96	Germany	Abstract
JL	EP 0 232 719 A1	01/10/87	Europe	Abstract
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